

FORM PTO-1449 (modified) To: U.S. Department of Commerce (PW FORM PAT-1449) Patent and Trademark Office				Atty. Dkt. No.	M#	Client Ref.:
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**INFORMATION DISCLOSURE STATEMENT
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Date: December 28, 2009

Page **1** of **1**

Applicant: OKUBO et al.

Appln. No.: 10/544,178

Filing Date: April 24, 2006

Examiner: MOORE, W. Group Art Unit: 2826

U.S. PATENT DOCUMENTS

Examiner's Initials*	Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
AR						
BR						
CR						
DR						
ER						
FR						
GR						
HR						
IR						
JR						
KR						
LR						
MR						
NR						

FOREIGN PATENT DOCUMENTS

	Document Number	Date MM/YYYY	Country	Inventor Name	English Abstract		Translation Readily Available	
					Enclosed	No	Enclose	No
OR	2000-329716 A	11-30-2000	Japan	KUSAKA TAKAO	X			
PR								
QR								
RR								
SR								
TR								
UR								
VR								
WR								
XR								

OTHER (Including in this order Author, Title, Periodical Name, Date, Pertinent Pages, etc.)

YR	"Kunio Takayanagi et al., "Semiconductor Measurement Evaluation Dictionary", Japan Science Forum Corporation, September 12, 1997, pages 87-90			X
ZR	Notice of Reasons for Rejection for Japanese Application No. 2004-567897 dated November 4, 2009			X
AAR				
BBR				

Examiner

Date Considered:

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.